## MAY 2 5 2007

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

398°	
Application Serial No	10/609,311
Filing Date	June 26, 2003
Inventor	Donald L. Yates
Assignee	Micron Technology, Inc.
	1756
	Kathleen Duda
Attorney's Docket No	MI22-2236
Customer No	021567
Title	Semiconductor Processing Patterning Methods

## SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Reference - - See attached Form PTO-1449

The attached Form PTO-1449 is submitted in compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98. Pursuant to Federal Register Vol. 69, No. 182, pg. 56542 (September 21, 2004), no copies of any cited U.S. patents or U.S. published applications are included herewith. No admission is made regarding whether the submitted reference is prior art.

This Supplemental Information Disclosure Statement is being filed with a Response to Final Office Action to Accompany Request for Continued Examination (RCE). Therefore, no fee is believed to be required. However, in the event that a fee is required for filing this Supplemental Information Disclosure Statement, please charge the fee specified under 37 C.F.R. § 1.17(p) to Deposit Account No. 23-0925

Citation of these references is respectfully requested.

Respectfully submitted,

Date: 5/22/07

Robert C. Hyta Reg. No. 46,791

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## U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO. MI22-2236

SERIAL NO. 10/609,311

IST OF ART CITED BY APPLICANT

(Use several sheets if necessary)

APPLICANT: Donald L. Yates

FILING DATE

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U.S. PATENT DOCUMENTS										
*Examiner's Initials		Document Number	Date	Name		Class	Subclass	ubclass Filing Date If Appropriate		
	AA	6,169,019	01/01	Takagi						
	AB	6,943,126	09/05	Narayanan et al.						
	AC	2004/0219736	11/04	Yoshitaka						
	AD	2005/0035460	02/05	Tseng						
	AE	2005/0266619	12/05	Brask et al.						
	AF	2005/026664	12/05	Harrison et al.						
	AG	2006/0064969	05/02	Havemann						
	АН	2006/0183277	08/06	Brask et al.						
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FOREIGN F	ATEN	T DOCUMENTS		·				,		
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